

Claims

1. A probe for connecting a device under test with at least one trace of a test circuitry comprising:
a body;
a contact area with a plurality of contact points to contact said at least one trace;
at least one arm for engaging at least one lead of said device under test;
at least one means of receiving at least one spring means;
and
at least secondary support means
whereby
probe can maintain electrical contact with said at least one trace as said at least one trace is worn with use.
2. A probe according to Claim 1, wherein shape of said body may be varied to enable said probe to fit in a test socket.
3. A probe according to Claim 1, wherein said plurality of contact points may on a continuous curve.
4. A probe according to Claim 1, wherein said plurality of contact points may discrete bumps on said contact area.
5. A probe according to Claim 1, wherein contact area of said arm engaging said lead is toothed.
6. A probe according to Claim 1, wherein contact area of said arm engaging said lead is cross-hatched.

7. A probe according to Claim 1, wherein said at least one means of receiving at least one spring means is a notch.
8. A probe according to Claim 1, wherein said at least secondary support means is a curved leg.
9. A probe according to Claim 1, wherein said at least secondary support means is a loop.
10. A probe according to Claim 1, wherein said at least secondary support means is W-shaped.